


<b>Search Notes</b>  	<b>Application/Control No.</b>  10734164	<b>Applicant(s)/Patent Under Reexamination</b>  CHANG, DEUK-HWAN
	<b>Examiner</b>  Cheukfan Lee	<b>Art Unit</b>  2625

SEARCHED			
Class	Subclass	Date	Examiner
358	496,498,494,505,474,492	3/31/2008	C.Lee
399	377,378	3/31/2008	C.Lee
355	75	3/31/2008	C.Lee

SEARCH NOTES		
Search Notes	Date	Examiner
EAST search: Inventor search, see history	3/31/2008	C.Lee

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
358	496,498,494,474	3/31/2008	C.Lee